


<b>Search Notes</b>  	<b>Application/Control No.</b>  10580401	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  Awet Haile	<b>Art Unit</b>  2474

SEARCHED			
Class	Subclass	Date	Examiner
370	395.2, 395.5, 252	10/31/2009	MA
370	231, 232, 233, 235, 236.1, 395.5, 468	5/7/2010	A.H

SEARCH NOTES		
Search Notes	Date	Examiner
East Search (updated)	2/17/2009	MA
Inventor's/Asignee's Search	10/31/2009	MA
NPL(IEEE, Books and so)	10/31/2009	MA
PLUS Search	10/31/2009	MA
Google/patents/scholar	10/31/2009	Ma
East text search	5/7/2010	A.H
East class/subclass limited search 370/395.5, 370/236.1	5/7/2010	A.H
Inventor's search	5/7/2010	A.H

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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